

Search Notes

Application/Control No.

09/539,409

Examiner

Anand Bhatnagar

Applicant(s)/Patent under
Reexamination

YAMADA, MASAHIKO

Art Unit

2624

SEARCHED

Class	Subclass	Date	Examiner
382	100,128, 130, 131,132	2/18/2007	AB
128	922	2/18/2007	AB
text	see sheet	2/18/2007	AB
updated	see sheet	2/18/2007	AB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
See Interference printout		2/18/2007	AB

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
382/100,128,130- 132;128/922;600/407- 415;707/1,100,101,102,103R,200.ccls.	2/18/2007	AB
Inventor	2/18/2007	AB
IEEE	2/18/2007	AB
((radiation x-ray\$4 xray\$4) and imag\$4 and (point\$ location\$1 cursor\$1 marker\$1 fiducial\$4 position\$4) and stor\$6.....	2/18/2007	AB